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- 3-State Bus Driving Inverting Outputs
- Buffered Control Inputs
- Package Options Include Plastic Small-Outline (DW), Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

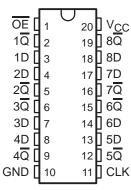
description

These octal D-type edge-triggered flip-flops feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

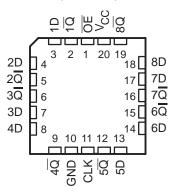
On the positive transition of the clock (CLK) input, the $\overline{\mathbb{Q}}$ outputs are set to the complement of the logic states set up at the data (D) inputs. The 'ALS534A and SN74AS534 have inverted outputs, but otherwise are functionally equivalent to the 'ALS374A and SN74AS374.

A buffered output-enable (\overline{OE}) input places the eight outputs in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components.

SN54ALS534A . . . J PACKAGE SN74ALS534A, SN74AS534 . . . DW OR N PACKAGE (TOP VIEW)



SN54ALS534A . . . FK PACKAGE (TOP VIEW)



OE does not affect the internal operations of the flip-flops. Old data can be retained or new data can be entered while the outputs are off.

The SN54ALS534A is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74ALS534A and SN74AS534 are characterized for operation from 0°C to 70°C.

FUNCTION TABLE (each flip-flop)

	INPUTS		OUTPUT
OE	CLK	D	Q
L	1	Н	L
L	\uparrow	L	Н
L	H or L	Χ	\overline{Q}_0
Н	Χ	Χ	Z



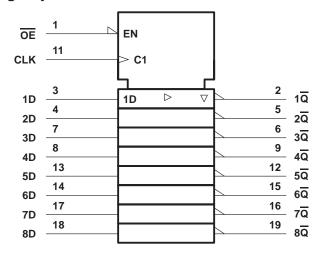
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SN54ALS534A, SN74ALS534A, SN74AS534 OCTAL D-TYPE EDGE-TRIGGERED FLIP-FLOPS WITH 3-STATE OUTPUTS

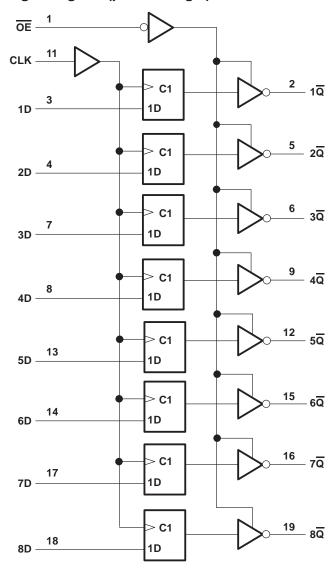
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logic symbol[†]



[†]This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}	7 V
Input voltage, V _I	7 V
Voltage applied to a disabled 3-state output	5.5 V
Operating free-air temperature range, TA: SN54ALS534A	55°C to 125°C
SN74ALS534A	0°C to 70°C
Storage temperature range, Teta	65°C to 150°C

recommended operating conditions

		SN	SN54ALS534A SN74ALS534A		4A	UNIT		
		MIN	NOM	MAX	MIN	NOM	MAX	UNII
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
V_{IL}	Low-level input voltage			0.7			0.8	V
IOH	High-level output current			-1			-2.6	mA
lOL	Low-level output current			12			24	mA
fclock	Clock frequency	0		30	0		35	MHz
t _W	Pulse duration, CLK high or low	16.5			14			ns
t _{su}	Setup time, data before CLK↑	10			10			ns
t _h	Hold time, data after CLK↑	0			0			ns
TA	Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DAI	DAMETER	TECT OF	ONDITIONS	SN5	4ALS53	4A	SN74ALS534A			UNIT
PARAMETER		1531 C	TEST CONDITIONS		TYP‡	MAX	MIN	TYP‡	MAX	UNII
٧ _{IK}		$V_{CC} = 4.5 \text{ V},$	$I_{I} = -18 \text{ mA}$			-1.5			-1.5	V
		$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -0.4 \text{ mA}$	V _{CC} -2	2		VCC -2	2		
Vон		V _{CC} = 4.5 V	I _{OH} = −1 mA	2.4	3.3					V
		VCC = 4.5 V	$I_{OH} = -2.6 \text{ mA}$				2.4	3.2		
V		V 45V	I _{OL} = 12 mA		0.25	0.4		0.25	0.4	V
VOL		V _{CC} = 4.5 V	I _{OL} = 24 mA					0.35	0.5	V
lozh		$V_{CC} = 5.5 V,$	V _O = 2.7 V			20			20	μΑ
lozL		V _{CC} = 5.5 V,	V _O = 0.4 V			-20			-20	μΑ
lį		V _{CC} = 5.5 V,	V _I = 7 V			0.1			0.1	mA
lн		V _{CC} = 5.5 V,	V _I = 2.7 V			20			20	μΑ
1	CLK, OE	DE V 55V	V: 0.4.V			-0.1			-0.1	A
IIL	D V _{CC} = 5.5 V,		V _I = 0.4 V		-0.2				-0.2	mA
ΙΟ§		V _{CC} = 5.5 V,	V _O = 2.25 V	-20		-112	-30		-112	mA
			Outputs high		11	19		11	19	
ICC		V _{CC} = 5.5 V	Outputs low		19	28		19	28	mA
			Outputs disabled		10	31		20	31	

[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

[§] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.



[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

SN54ALS534A, SN74ALS534A, SN74AS534 OCTAL D-TYPE EDGE-TRIGGERED FLIP-FLOPS WITH 3-STATE OUTPUTS

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switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 4.5 V to 5.5 V, C_L = 50 pF, R1 = 500 Ω , R2 = 500 Ω , T_A = MIN to MAX †		$\begin{array}{c} \text{C}_{\text{L}} = 50 \text{ pF,} \\ \text{R1} = 500 \ \Omega, \\ \text{TO} \\ \text{(OUTPUT)} \\ \end{array}$ $\begin{array}{c} \text{R2} = 500 \ \Omega, \\ \text{T}_{\text{A}} = \text{MIN to MA} \end{array}$			UNIT
		5	SN54ALS534A		SN74ALS534A			
			MIN	MAX	MIN	MAX		
f _{max}			30		35		MHz	
t _{PLH}	CLK	A -	3	17	3	12	ns	
t _{PHL}	OLK	Any Q	4	18	4	16	115	
^t PZH	ŌĒ	A	3	19	3	17	ns	
t _{PZL}	OE .	Any Q	4	20	4	18	115	
^t PHZ	ŌĒ	Any Q	1	12	1	10	ns	
t _{PLZ}	OE .	Ally Q	1	25	2	14	115	

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage, V _{CC}	7 V
Input voltage, V _I	7 V
Voltage applied to a disabled 3-state output	5.5 V
Operating free-air temperature range, T _A : SN74AS534	0°C to 70°C
Storage temperature rang, T _{stg}	−65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

			SI	SN74AS534		
			MIN	MIN NOM MAX 4.5 5 5.5 2 0.8 -15 48 0 125 1 4 3 2	UNIT	
Vсс	Supply voltage		4.5	5	5.5	V
VIH			2			V
V_{IL}	i				0.8	V
ІОН	OH High-level output current				-15	mA
loL	Low-level output current				48	mA
fclock	Clock frequency		0		125	MHz
	Pulse duration	CLK high	4			no
t _W	ruise duration	CLK low	3			ns
t _{su}	Setup time, data before CLK↑		2			ns
t _h	Hold time, data after CLK↑		2			ns
T _A	Operating free-air temperature		0		70	°C

SN54ALS534A, SN74ALS534A, SN74AS534 OCTAL D-TYPE EDGE-TRIGGERED FLIP-FLOPS WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST COND	NTIONS	SN	174AS53	34	UNIT	
PARAMETER	TEST COND	ITIONS	MIN	TYP	MAX	UNII	
VIK	V _{CC} = 4.5 V,	I _I = -18 mA			-1.2	V	
Vari	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -2 \text{ mA}$	V _{CC} -2	2		V	
Voн	V _{CC} = 4.5 V,	I _{OH} = -15 mA	2.4	3.3		V	
V _{OL}	V _{CC} = 4.5 V,	I _{OL} = 48 mA		0.34	0.5	V	
lozh	V _{CC} = 5.5 V,	V _O = 2.7 V			50	μΑ	
lozL	V _{CC} = 5.5 V,	V _I = 0.4 V			-50	μΑ	
II	V _{CC} = 5.5 V,	V _I = 7 V			0.1	mA	
IIH	V _{CC} = 5.5 V,	V _I = 2.7 V			20	μΑ	
OE, CLK	V 55V	V: 0.4V			-0.5	A	
IIL D	$V_{CC} = 5.5 V$	V _I = 0.4 V			-2	mA	
1 _O ‡	V _{CC} = 5.5 V,	V _O = 2.25 V	-30		-112	mA	
		Outputs high		77	120		
Icc	$V_{CC} = 5.5 V$	Outputs low		84	128	mA	
		Outputs disabled		84	128		

[†] All typical values are at V_{CC} = 5 V, T_A = 25°C.

switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	C _L = 50 pF R1 = 500 Ω R2 = 500 Ω T _A = MIN t	V_{CC} = 4.5 V to 5.5 V, C_L = 50 pF, R1 = 500 Ω, R2 = 500 Ω, T_A = MIN to MAX§	
			MIN	MAX	
f _{max}			125		MHz
^t PLH	CLK	A G	3	8	ns
^t PHL	CLK	CLK Any Q	4	9	115
^t PZH		. =	2	6	
tPZL	ŌĒ	Any Q	3	10	ns
t _{PHZ}	ŌĒ	Any Q	2	6	ns
t _{PLZ}	OE .	Ally Q	2	6	1115

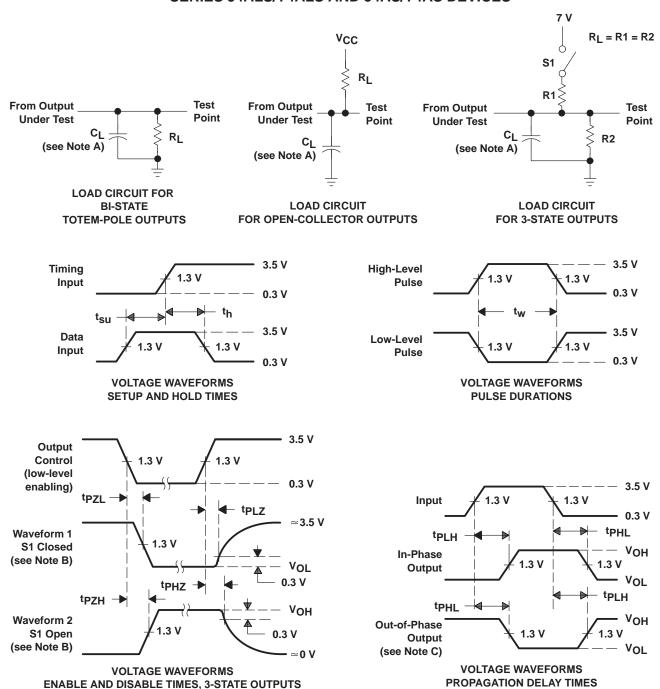
[§] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



[‡] The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

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PARAMETER MEASUREMENT INFORMATION SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



NOTES: A. C_I includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: $PRR \le 1$ MHz, $t_f = t_f = 2$ ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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